


<b>Search Notes</b>  	<b>Application/Control No.</b>  10550790	<b>Applicant(s)/Patent Under Reexamination</b>  MARIKAWA ET AL.
	<b>Examiner</b>  NAEEM HAQ	<b>Art Unit</b>  3625

SEARCHED			
Class	Subclass	Date	Examiner
705	26,27	3/23/2010	NH
705	26,27	10/11/2010	NH

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/NAEEM HAQ/ Primary Examiner.Art Unit 3625
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